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To thoroughly validate the charge identification and spatial resolution capabilities of L0 and its ladders, we conducted multiple beam tests at CERN. These tests include beams of heavy ions and muons. In this work, we will first introduce the relevant background information, with a detailed discussion of the experimental setup used in the recent L0 beam tests. Specifically, we installed two sets of beam telescopes, one upstream and one downstream with respect to the ladder to reconstruct particle trajectories. This let us estimate the particles position at the ladder location with a precision of approximately $2\text{ }\mu\text{m}$. We also exploited a charge detector to assist in analyzing the charge resolution of the ladder in offline analysis by having a precise reference. Finally, we will present and discuss the preliminary results from these L0 beam tests.

Authors: OLIVA, Alberto (Universita e INFN, Bologna (IT)); MIAO, Dexing (The Institute of High Energy Physics of the Chinese Academy of Sciences (CN)); SILVESTRE, Gianluigi (INFN Perugia (IT)); AMBROSI, Giovanni (Universita e INFN, Perugia (IT)); WANG, Jianchun (Chinese Academy of Sciences (CN)); PACINI, Lorenzo (INFN, Firenze (IT)); MOBILEANU, Maria; DURANTI, Matteo (Universita e INFN, Perugia (IT)); BARBANERA, Mattia (Universita e INFN, Perugia (IT)); GRAZIANI, Maura (Universita e INFN, Perugia (IT)); FENG, Mingjie (Chinese Academy of Sciences (CN)); MORI, Nicola (INFN Florence); STARODUBTSEV, Oleksandr (Universita e INFN, Firenze (IT)); Dr BETTI, Pietro (INFN sezione di Firenze); LIU, Pingcheng (Shandong Institute of Advanced

Technology (CN)); LI, Qinze (Chinese Academy of Sciences (CN)); DETTI, Sebastiano (Universita e INFN, Firenze (IT)); SHENG, Shuqi (Chinese Academy of Sciences (CN)); LI, Tiange (Hunan University (CN)); FORMATO, Valerio (INFN - Sezione di Roma Tor Vergata); KOUTSENKO, Vladimir (Massachusetts Inst. of Technology (US)); JIANG, Xiaojie (Chinese Academy of Sciences (CN)); CAI, Xudong (Massachusetts Inst. of Technology (US)); JIANG, Yaozu (Universita e INFN, Perugia (IT)); WU, Zibing (Shandong University (CN)); XU, Zijun (Chinese Academy of Sciences (CN))

Presenter: JIANG, Yaozu (Universita e INFN, Perugia (IT))

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